


<b>Search Notes</b>  	<b>Application/Control No.</b>  10817249	<b>Applicant(s)/Patent Under Reexamination</b>  NAKANO ET AL.
	<b>Examiner</b>  RYAN D WALSH	<b>Art Unit</b>  2852

SEARCHED			
Class	Subclass	Date	Examiner
399	71	4/28/2008	RDW
399	350	4/28/2008	RDW
399	351	4/28/2008	RDW

SEARCH NOTES		
Search Notes	Date	Examiner
See East History	4/28/2008	RDW

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
399	350	4/28/2008	RDW